

Notice of References Cited

Application/Control No.

10/603,700

Applicant(s)/Patent Under
Reexamination
MOORE ET AL.

Examiner

MATTHEW J. BROPHY

Art Unit

2191

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0144245 A1	10-2002	Lueh, Guei-Yuan	717/140
*	B	US-6,493,868 B1	12-2002	DaSilva et al.	717/105
*	C	US-6,795,963 B1	09-2004	Andersen et al.	717/130
*	D	US-6,928,449 B2	08-2005	Ten-Hove et al.	707/102
*	E	US-7,293,260 B1	11-2007	Dmitriev, Mikhail A.	717/130
*	F	US-7,293,259 B1	11-2007	Dmitriev, Mikhail A.	717/130
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lourenco, J., Cunha, J., Krawczyk, H., Kuzora, P., Neyman, M., & Wiszniewski, B. "An integrated testing and debugging environment for parallel and distributed programs." EUROMICRO 97. 'New Frontiers of Information Technology', Proceedings of the 23rd EUROMICRO Conference 23(1997): 291-296.
	V	DeRose, L. Hoover T. Hollingsworth, J.. "The dynamic probe class library-an infrastructure for developing instrumentation for performance tools." Parallel and Distributed Processing Symposium., Proceedings 15th International 15(2001): 7.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.